

## PATENT ABSTRACTS OF JAPAN

(11)Publication number : 10-172488  
 (43)Date of publication of application : 26.06.1998

(51)Int.Cl. H01J 37/21  
 H01J 37/22

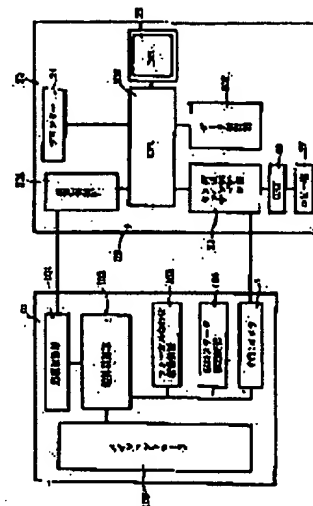
(21)Application number : 08-353017 (71)Applicant : BRIDGESTONE CORP  
 NIRECO CORP  
 (22)Date of filing : 13.12.1996 (72)Inventor : UTSUKI HIROYUKI  
 MAEHARA AKIHITO  
 KANAME HIROMITSU

## (54) AUTOMATIC MEASURING METHOD AND DEVICE OF MICRO-PARTICLE FORM

## (57)Abstract:

PROBLEM TO BE SOLVED: To ensure efficient and light measuring by making manual operation only initial operation and controlling position movement and focusing of a sample stage by an external device.

SOLUTION: In a measurement viewing field range of a measurement sample, a sample stage is manually moved to a measurement start point, focusing is performed manually, an X-axis from a transmission type electronic microscope TEM to a measurement start point, a Y-axis, and a Z-axis when a focus is adjusted or a detected value of a lens current value is stored as communication data in a control computer, and initial setting is performed. By incorporating automatic measurement software in which coordinate software of a sample stage is built in a CPU203, position movement of a measurement viewing field point of the sample stage is not automatically performed. By incorporating focus control software for controlling a focus according to an X-Y coordinate at a measurement viewing point set for a CPU203, focusing every measurement viewing field point is automatically performed.



## LEGAL STATUS

[Date of request for examination]  
 [Date of sending the examiner's decision of rejection]  
 [Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]  
 [Date of final disposal for application]  
 [Patent number]  
 [Date of registration]  
 [Number of appeal against examiner's decision of rejection]  
 [Date of requesting appeal against examiner's decision of rejection]  
 [Date of extinction of right]

Copyright (C); 1998,2000 Japanese Patent Office